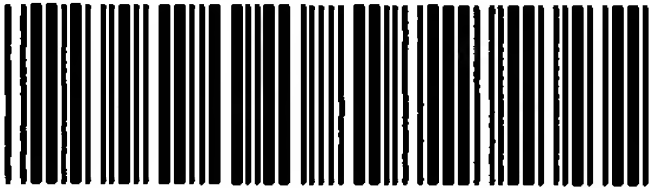


<div>Search Notes</div> 	<div>Application/Control No.</div> <div>10630711</div>	<div>Applicant(s)/Patent Under Reexamination</div> <div>LEE, JU-YUP</div>
	<div>Examiner</div> <div>Tekle, Daniel</div>	<div>Art Unit</div> <div>2621</div>

SEARCHED			
Class	Subclass	Date	Examiner
348	565, 589, 584	06/07/07	D.T.

SEARCH NOTES		
Search Notes	Date	Examiner
EAST DATA BASE (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	06/07/07	D.T.
COMBINED CITATION	06/07/07	D.T.
SEARCH QUERY ATTACHED	06/07/07	D.T.
INVENTOR SEARCH	06/01/07	D.T.
SEARCH UPDATED	11/13/07	D.T.

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner